

# OptiMOS<sup>™</sup> P3 Power-Transistor

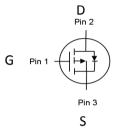
#### **Features**

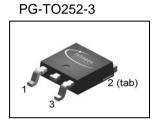
- single P-Channel (Logic Level)
- Enhancement mode
- Qualified according JEDEC<sup>1)</sup> for target applications
- 175 °C operating temperature
- Pb-free; RoHS compliant
- applications: load switch, HS-switch
- Halogen-free according to IEC61249-2-21



#### **Product Summary**

V <sub>DS</sub>		-30	V
$R_{\rm DS(on),max}$ $V_{\rm GS} =$	10V	4.2	mΩ
$V_{GS} =$	4.5V	6.8	
I <sub>D</sub>		-70	Α





Туре	Package	Marking	Lead free	Packing
IPD042P03L3 G	PG-TO252-3	042P03L	Yes	non dry

#### **Maximum ratings,** at $T_i$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C	-70	А
		T <sub>C</sub> =100 °C	-70	]
Pulsed drain current	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C <sup>2)</sup>	-280	]
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{\rm D}$ =-70 A, $R_{\rm GS}$ =25 $\Omega$	269	mJ
Gate source voltage	$V_{GS}$		±20	V
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	150	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
ESD class		JESD22-A114 HBM	class 2 ( 2 kV - < 4 kV)	
Soldering temperature			260	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

<sup>1)</sup> J-STD20 and JESD22



Parameter	Symbol	Symbol Conditions		Values		
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	$R_{thJC}$		-	-	1.0	K/W
Thermal resistance, junction - ambient	$R_{thJA}$	6 cm <sup>2</sup> cooling area <sup>2)</sup>	-	-	50	

# **Electrical characteristics,** at $T_i$ =25 °C, unless otherwise specified

#### **Static characteristics**

Drain-source breakdown voltage	Drain-source breakdown voltage $V_{(BR)DSS}$ $V_{GS}$ =0 V, $I_D$ =-250μA		-30	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-270 μA	-2.0	-1.5	-1.0	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS}$ =-30 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	1	1	-1	μA
		V <sub>DS</sub> =-30 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =175 °C	-	-	-300	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =-20 V, V <sub>DS</sub> =0 V	-	-10	-100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =-4.5 V, I <sub>D</sub> =-70 A	-	4.6	6.8	mΩ
		V <sub>GS</sub> =-10 V, I <sub>D</sub> =-70 A	-	3.5	4.2	
Gate resistance	$R_{G}$		-	2.4	-	Ω
Transconductance	$g_{fs}$	$ V_{\rm DS}  > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = -70~{\rm A}$	65	130	1	S

 $<sup>^{2)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	9290	12400	pF
Output capacitance	Coss	$V_{GS}$ =0 V, $V_{DS}$ =-15 V, $f$ =1 MHz	-	3570	4750	
Reverse transfer capacitance	C <sub>rss</sub>		-	150	220	
Turn-on delay time	t <sub>d(on)</sub>		-	21	33	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =-15 V, V <sub>GS</sub> =- 10 V, I <sub>D</sub> =-70 A,	-	167	251	
Turn-off delay time	$t_{d(off)}$	$R_{G,ext}=6 \Omega$	-	89	134	
Fall time	t <sub>f</sub>		-	22	33	1
Gate Charge Characteristics <sup>3)</sup>						
Gate to source charge	Q <sub>gs</sub>		-	31	41	nC
Gate charge at threshold	Q <sub>g(th)</sub>	]	-	15	20	1
Gate to drain charge	Q <sub>gd</sub>	V <sub>DD</sub> =-15 V, I <sub>D</sub> =-70 A,	-	14	21	
Switching charge	Q <sub>sw</sub>	V <sub>GS</sub> =0 to -10 V	-	30	42	
Gate charge total	Qg		-	131	175	]
Gate plateau voltage	V <sub>plateau</sub>		-	3.3	-	V
Output charge	Q <sub>oss</sub>	V <sub>DD</sub> =-15 V, V <sub>GS</sub> =0 V	-	84	111	nC
Reverse Diode	•			•		
Diode continous forward current	Is	T 25 °C	-	-	70	А
Diode pulse current	I <sub>S,pulse</sub>	- T <sub>C</sub> =25 °C	-	-	280	1
Diode forward voltage	$V_{\mathrm{SD}}$	V <sub>GS</sub> =0 V, I <sub>F</sub> =-70 A, T <sub>j</sub> =25 °C	-	-	-1.1	V
Reverse recovery time	t <sub>rr</sub>	$V_R$ =15 V, $I_F$ = $ I_S $ , $di_F/dt$ =100 A/ $\mu$ s	-	54	68	ns
Reverse recovery charge	Q <sub>rr</sub>		-	61	76	nC



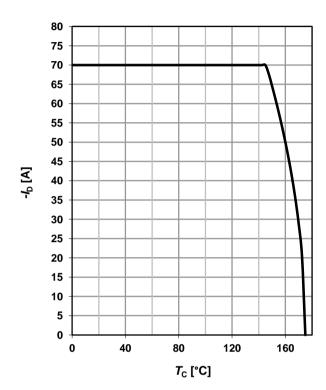
#### 1 Power dissipation

## $P_{\text{tot}} = f(T_{\text{C}}); t_{\text{p}} \le 10 \text{ s}$

#### $T_C$ [°C]

#### 2 Drain current

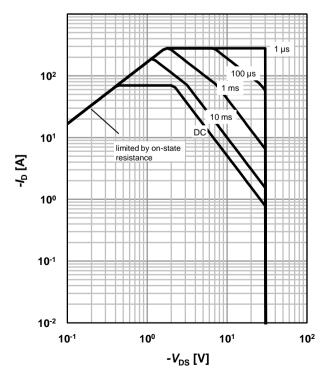
$$I_{D}=f(T_{C}); |V_{GS}| \ge 10 \text{ V}; t_{p} \le 10 \text{ s}$$



## 3 Safe operating area

 $I_D = f(V_{DS}); T_C = 25 \text{ °C}^{1)}; D = 0$ 

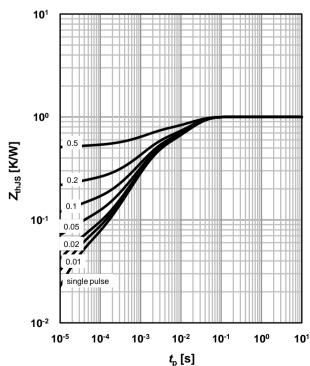
parameter:  $t_p$ 



#### 4 Max. transient thermal impedance

 $Z_{\text{thJS}} = f(t_p)$ 

parameter:  $D=t_p/T$ 

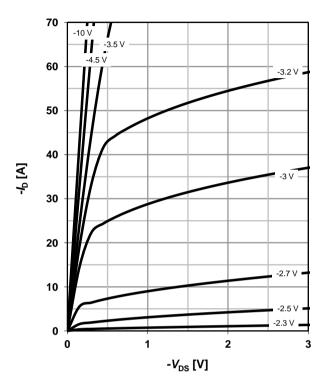




#### 5 Typ. output characteristics

 $I_D=f(V_{DS}); T_i=25 °C$ 

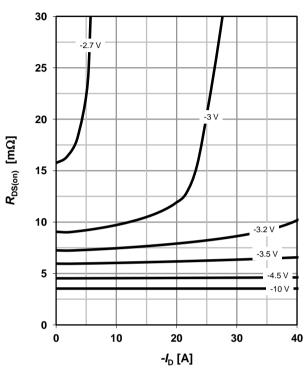
parameter: V<sub>GS</sub>



#### 6 Typ. drain-source on resistance

 $R_{DS(on)}=f(I_D); T_j=25 °C$ 

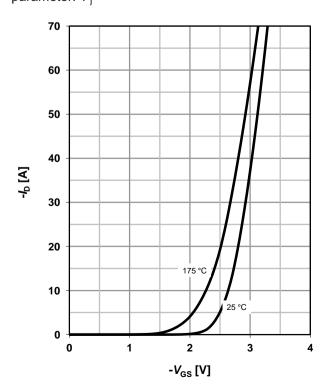
parameter: V<sub>GS</sub>



#### 7 Typ. transfer characteristics

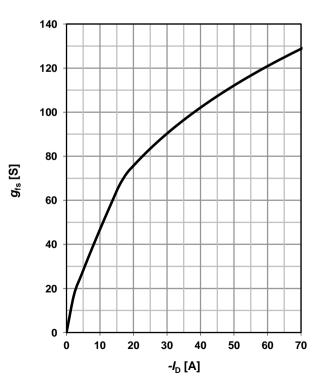
 $I_{D}=f(V_{GS}); |V_{DS}|>2|I_{D}|R_{DS(on)max}$ 

parameter:  $T_{\rm j}$ 



## 8 Typ. forward transconductance

$$g_{fs}=f(I_D); T_j=25 \text{ °C}$$



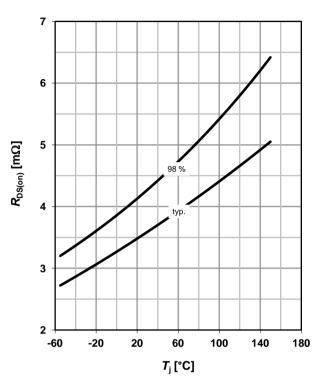


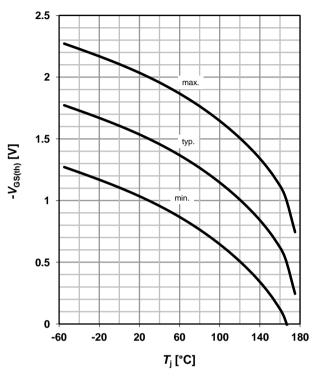
#### 9 Drain-source on-state resistance

 $R_{DS(on)} = f(T_i); I_D = -30 \text{ A}; V_{GS} = -10 \text{ V}$ 

## 10 Typ. gate threshold voltage

 $V_{GS(th)}=f(T_i); V_{GS}=V_{DS}; I_D=-270 \mu A$ 





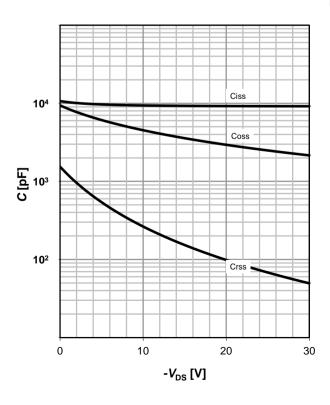
## 11 Typ. capacitances

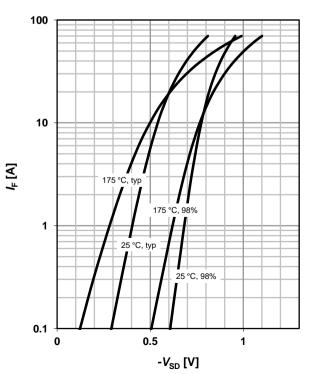
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$ 

#### 12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$ 

parameter:  $T_{\rm j}$ 





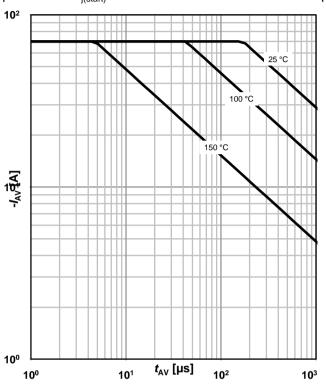


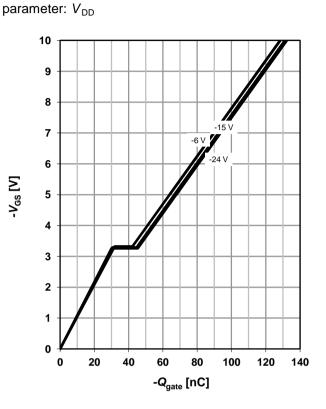
#### 13 Avalanche characteristics

 $I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$ 

parameter:  $T_{j(start)}$ 

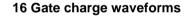
# 14 Typ. gate charge $V_{GS}$ =f( $Q_{gate}$ ); $I_D$ =-70 A pulsed

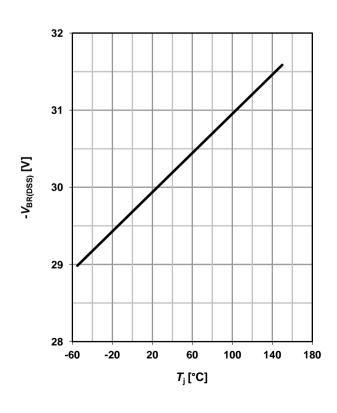


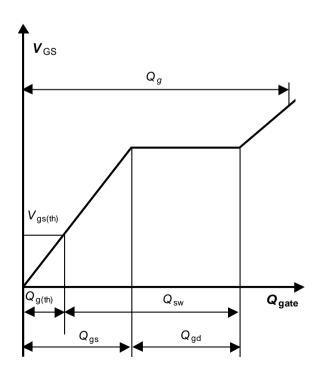


15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f( $T_i$ );  $I_D$ =-250  $\mu$ A



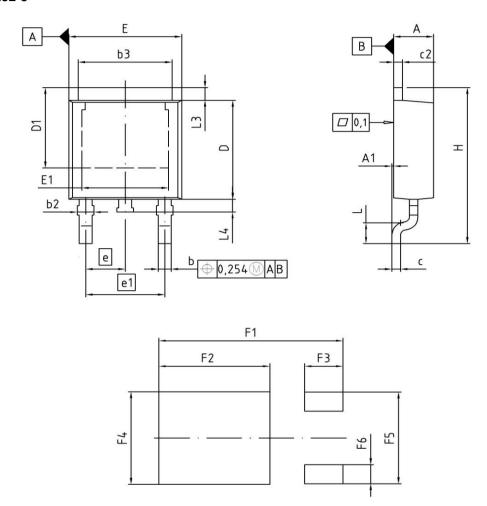




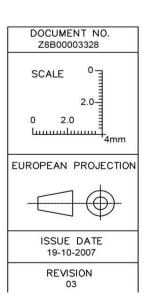


#### **Package Outline**

#### PG-TO252-3



DIM	MILLIN	MILLIMETERS		HES		
DIM	MIN	MAX	MIN	MAX		
Α	2.16	2.41	0.085	0.095		
A1	0.00	0.15	0.000	0.006		
Ь	0.64	0.89	0.025	0.035		
b2	0.65	1.15	0.026	0.045		
b3	5.00	5.50	0.197	0.217		
С	0.46	0.60	0.018	0.024		
c2	0.46	0.98	0.018	0.039		
D	5.97	6.22	0.235	0.245		
D1	5.02	5.84	0.198	0.230		
Ε	6.40	6.73	0.252	0.265		
E1	4.70	5.21	0.185	0.205		
е	2	2.29	0.0	0.090		
e1	4.57		0.1	80		
N		3	3			
Н	9.40	10.48	0.370	0.413		
L	1.18	1.70	0.046	0.067		
L3	0.90	1.25	0.035	0.049		
L4	0.51	1.00	0.020	0.039		
F1	10.50	10.70	0.413	0.421		
F2	6.30	6.50	0.248	0.256		
F3	2.10	2.30	0.083	0.091		
F4	5.70	5.90	0.224	0.232		
F5	5.66	5.86	0.223	0.231		
F6	1.10	1.30	0.043	0.051		





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